COMPLEMENTARY 40V ENHANCEMENT MODE MOSFET

SUMMARY

N-Channel = $V_{(BR)DSS}$ = 40V : $R_{DS(on)}$ = 0.05 Ω ; I_D = 5.2A

P-Channel = $V_{(BR)DSS}$ = -40V : $R_{DS(on)}$ = 0.06 Ω ; I_D = -4.7A

DESCRIPTION

This new generation of trench MOSFETs from Zetex utilises a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.

FEATURES

- Low on-resistance
- · Fast switching speed
- Low threshold
- Low gate drive
- Low profile SOIC package

APPLICATIONS

- Motor drive
- LCD backlighting

ORDERING INFORMATION

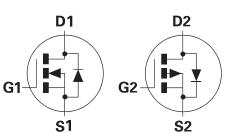
DEVICE	REEL SIZE	TAPE WIDTH	QUANTITY PER REEL
ZXMC4A16DN8TA	7″	12mm	500
ZXMC4A16DN8TC	13″	12mm	2,500

DEVICE MARKING

• ZXMC

4A16

ISSUE 1 - NOVEMBER 2004







C1		
S1	0	
G1	Dual	□D1
S2 🖂	Device	□D2
G2 🖂		⊨D2

TOP VIEW





ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	N-channel	P-channe	UNIT
Drain-source voltage	V _{DSS}	40	-40	V
Gate-source voltage	V _{GS}	±20	±20	V
Continuous drain current	I _D			
(V _{GS} = 10V; T _A =25°C) ^{(b)(d)}		5.2	-4.7	A
$(V_{GS} = 10V; T_A = 70^{\circ}C)^{(b)(d)}$		4.1	-3.8	A
$(V_{GS} = 10V; T_A = 25^{\circ}C)^{(a)(d)}$		4.0	-3.6	A
Pulsed drain current ^(c)	I _{DM}	24	-23	А
Continuous source current (body diode) ^(b)	I _S	2.5	2.3	А
Pulsed source current (body diode) ^(c)	I _{SM}	24	23	А
Power dissipation at $T_A = 25 \degree C^{(a)}$	PD	1.25		W
Linear derating factor		10		mW/°C
Power dissipation at $T_A = 25 \degree C^{(a)}$	P _D	1.8		W
Linear derating factor		14		mW/°C
Power dissipation at $T_A = 25 \degree C^{(b)}$ (d)	P _D	2.1		W
Linear derating factor		1	mW/°C	
Operating and storage temperature range	T _j , T _{stg}	-55 to	o +150	°C

THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to ambient ^{(a) (d)}	$R_{\Theta JA}$	100	°C/W
Junction to ambient ^{(a) (e)}	R _{0JA}	70	°C/W
Junction to ambient $^{(b)}$ $^{(d)}$	R _{0JA}	60	°C/W

NOTES

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

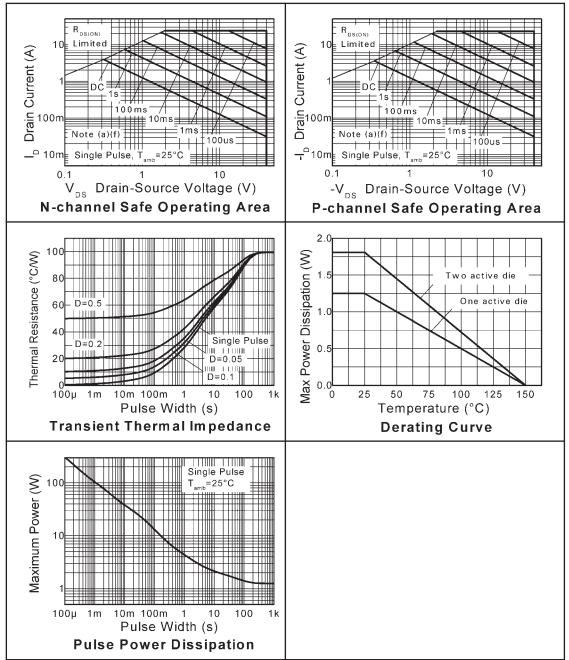
(b) For a device surface mounted on FR4 PCB measured at t \leq 10 sec.

(c) Repetitive rating - pulse width limited by maximum junction temperature. Pulse width 300us, d<= 0.02. Refer to Transient Thermal Impedance graph.

(d) For device with one active die.

(e) For device with two active die running at equal power.





TYPICAL CHARACTERISTICS



PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS	
STATIC						1	
Drain-Source Breakdown Voltage	V _{(BR)DSS}	40			V	$I_{D} = 250 \mu A, V_{GS} = 0V$	
Zero Gate Voltage Drain Current	I _{DSS}			0.5	μA	V _{DS} =40V, V _{GS} =0V	
Gate-Body Leakage	I _{GSS}			100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$	
Gate-Source Threshold Voltage	V _{GS(th)}	1.0			V	$I_D = 250 \text{mA}, V_{DS} = V_{GS}$	
Static Drain-Source On-State Resistance ⁽¹⁾	R _{DS(on)}			0.050 0.075	Ω	V _{GS} = 10V, I _D = 4.5A V _{GS} = 4.5V, I _D = 3.2A	
Forward Transconductance ^{(1) (3)}	9 _{fs}		8.6		S	V _{DS} = 15V, I _D = 4.5A	
DYNAMIC ⁽³⁾						1	
Input Capacitance	Ciss		770		pF		
Output Capacitance	Coss		92		pF	V _{DS} = 40V, V _{GS} =0V f=1MHz	
Reverse Transfer Capacitance	Crss		61		pF		
SWITCHING ^{(2) (3)}							
Turn-On-Delay Time	td(on)		3.3		ns		
Rise Time	tr		4.7		ns		
Turn-Off Delay Time	td(off)		29		ns	V _{DD} = 30V, I _D = 1A R _G ≅6.0Ω, V _{GS} = 10V	
Fall Time	tf		14		ns		
Total Gate Charge	Qg		17		nC		
Gate-Source Charge	Qgs		2.5		nC	V _{DS} = 30V, V _{GS} = 10V	
Gate Drain Charge	Qgd		3.8		nC	I _D = 4.5A	
SOURCE-DRAIN DIODE							
Diode Forward Voltage ⁽¹⁾	VSD		0.8	0.95	V	T _j =25°C, I _S = 4.5A, V _{GS} =0V	
Reverse Recovery Time ⁽³⁾	trr		20		ns	T _j =25°C, I _S = 2.5A,	
Reverse Recovery Charge ⁽³⁾	Qrr		16		nC	di/dt=100A/µs	

ELECTRICAL CHARACTERISTICS (at T_{amb} = 25°C unless otherwise stated)

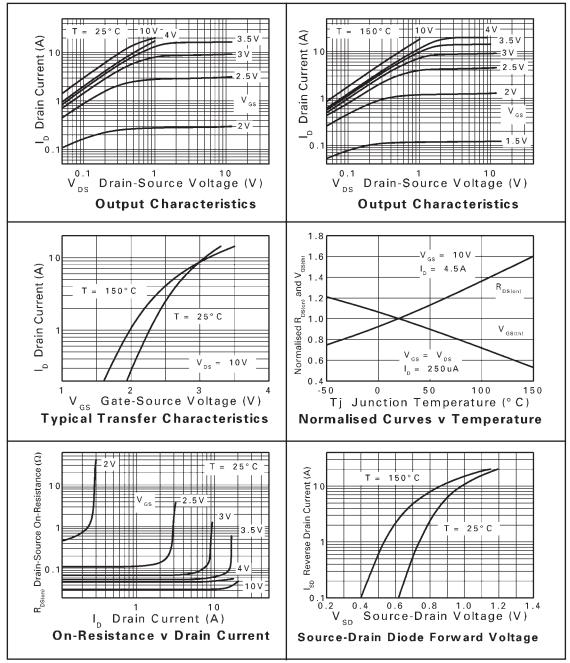
NOTES

(1) Measured under pulsed conditions. Pulse width \leq 300 μ s; duty cycle \leq 2%.

(2) Switching characteristics are independent of operating junction temperature.

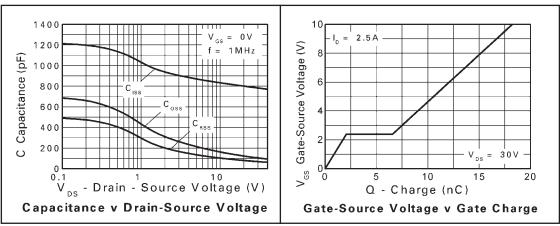
(3) For design aid only, not subject to production testing.





TYPICAL CHARACTERISTICS





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TYPICAL CHARACTERISTICS



PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS
STATIC	•					1
Drain-Source Breakdown Voltage	V _{(BR)DSS}	-40			V	I _D = -250μA, V _{GS} =0V
Zero Gate Voltage Drain Current	I _{DSS}			-1.0	μA	V _{DS} = -40V, V _{GS} =0V
Gate-Body Leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V
Gate-Source Threshold Voltage	V _{GS(th)}	-1.0			V	I_D = -250µA, V_{DS} = V_{GS}
Static Drain-Source On-State Resistance ⁽¹⁾	R _{DS(on)}			0.060 0.100	Ω	V _{GS} = -10V, I _D = -3.8A V _{GS} = -4.5V, I _D = -2.9A
Forward Transconductance ^{(1) (3)}	9 _{fs}		6.8		S	V _{DS} = -15V, I _D = -3.8A
DYNAMIC ⁽³⁾	•					
Input Capacitance	C _{iss}		1000		pF	
Output Capacitance	C _{oss}		180		pF	V _{DS} = -20V, V _{GS} =0V f=1MHz
Reverse Transfer Capacitance	C _{rss}		160		pF	
SWITCHING ^{(2) (3)}	-					1
Turn-On-Delay Time	t _{d(on)}		3.7		ns	
Rise Time	t _r		5.5		ns	V _{DD} = -20V, I _D = -1A
Turn-Off Delay Time	t _{d(off)}		33		ns	$R_G \cong 6.0\Omega, V_{GS} = 10V$
Fall Time	t _f		18		ns	
Gate Charge	Qg		15		nC	V _{DS} = -20V, V _{GS} = -5V I _D = -3.8A
Total Gate Charge	Qg		26		nC	N 0014 M 4014
Gate-Source Charge	Q _{gs}		3.2		nC	V _{DS} = -20V, V _{GS} = -10V I _D = -3.8A
Gate Drain Charge	Q _{gd}		7.3		nC	
SOURCE-DRAIN DIODE						
Diode Forward Voltage ⁽¹⁾	V _{SD}		-0.86	-0.95	V	T _j =25°C, I _S = -3.4A, V _{GS} =0V
Reverse Recovery Time ⁽³⁾	t _{rr}		27		ns	T _j =25°C, I _S = -3A,
Reverse Recovery Charge ⁽³⁾	Q _{rr}		25		nC	di/dt=100A/µs

ELECTRICAL CHARACTERISTICS (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

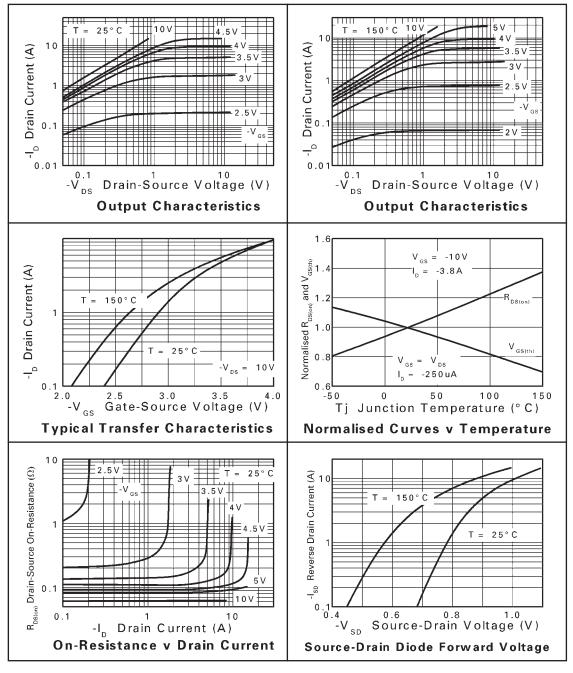
NOTES

(1) Measured under pulsed conditions. Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.

(2) Switching characteristics are independent of operating junction temperature.

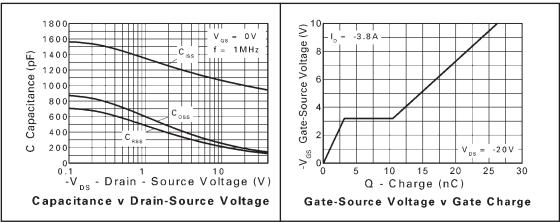
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TYPICAL CHARACTERISTICS

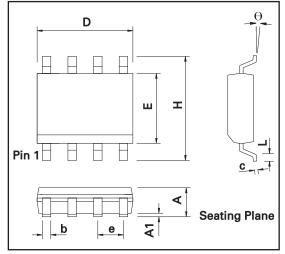




TYPICAL CHARACTERISTICS



PACKAGE OUTLINE



Controlling dimensions are in millimeters. Approximate conversions are given in inches

PACKAGE DIMENSIONS

DIM	Millim	neters	Inc	hes		DIM		Inches	
Dilvi	Min	Max	Min	Max	DIIVI	Min	Max	Min	Max
А	1.35	1.75	0.053	0.069	е	1.27 BSC		0.050 BSC	
A1	0.10	0.25	0.004	0.010	b	0.33	0.51	0.013	0.020
D	4.80	5.00	0.189	0.197	с	0.19	0.25	0.008	0.010
Н	5.80	6.20	0.228	0.244	θ	0°	8°	0°	8°
E	3.80	4.00	0.150	0.157	h	0.25	0.50	0.010	0.020
L	0.40	1.27	0.016	0.050	-	-	-	-	-

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